



<b>Session Title:</b>	<b>[WeG1] Frontier Metrology and Modeling III</b>
<b>Session Date:</b>	<b>November 13 (Wed.), 2024</b>
<b>Session Time:</b>	<b>09:10-10:40</b>
<b>Session Room:</b>	<b>Room G (Meeting Room, 5F, Grand Josun Busan)</b>
<b>Session Chair:</b>	<b>Prof. Sung Beom Cho (Ajou Univ., Korea)</b>

**[WeG1-1] [Invited]**

**09:10-09:40**

**Advancements in Metrology for Materials and Device Characterization: Exploring Innovative In-Materials Processing Techniques for Emerging Applications**

Mohit Kumar and Hyungtak Seo (Ajou Univ., Korea)

**[WeG1-2] [Invited]**

**09:40-10:10**

**Data Intelligence for Semiconductor Autonomous Fab**

Younghoon Sohn (Samsung Electronics Co., Ltd., Korea)

**[WeG1-3] [Invited]**

**10:10-10:40**

**Semiconductor Electronic Structure Measurement by Photoelectron Spectroscopy**

Jeong Won Kim (KRISS, Korea)